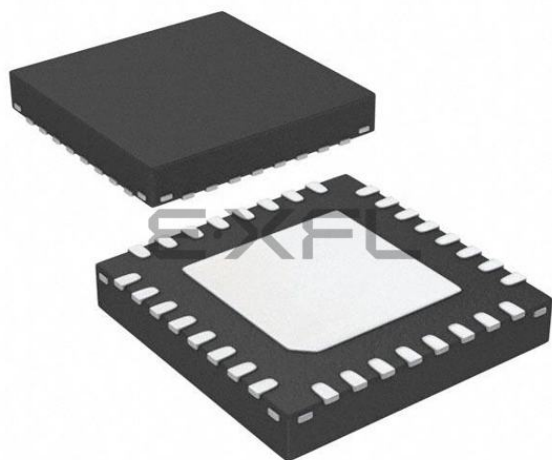




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Details

Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I ² C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	29
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	1.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f16e-a-qfn32r

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F32E-A-QFN32	32	2304	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F32E-A-QFP32	32	2304	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F32E-A-QFN24	32	2304	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-A-QSOP24	32	2304	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F32E-A-QFN32	32	2304	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F32E-A-QFP32	32	2304	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F32E-A-QFN24	32	2304	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-A-QSOP24	32	2304	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F16E-A-QFN32	16	1280	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F16E-A-QFP32	16	1280	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F16E-A-QFN24	16	1280	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-A-QSOP24	16	1280	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB10F16E-A-QFN32	16	1280	29	20	0	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB10F16E-A-QFP32	16	1280	28	20	0	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB10F16E-A-QFN24	16	1280	20	12	0	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-A-QSOP24	16	1280	21	13	0	6	7	Yes	-40 to +105 °C	QSOP24

3.7 Analog

14/12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 14-, 12-, and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 14-bit, 12-bit and 10-bit modes
- Supports an output update rate of up to 1 Msps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated factory-calibrated temperature sensor

12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
 - Internal connection to LDO output
 - Direct connection to GND
 - Direct connection to VDD
 - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ± 20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Temperature Sensor	I _{TSENSE}		—	75	120	μA
Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3) ⁶	I _{DAC}		—	125	—	μA
Comparators (CMP0, CMP1)	I _{CMP}	CPMD = 11	—	0.5	—	μA
		CPMD = 10	—	3	—	μA
		CPMD = 01	—	10	—	μA
		CPMD = 00	—	25	—	μA
Comparator Reference	I _{CPREF}		—	TBD	—	μA
Voltage Supply Monitor (VMON0)	I _{VMON}		—	15	20	μA

Note:

1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal LDO regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal LDO regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in low power mode. Total ADC + Reference current will depend on sampling rate.
6. DAC supply current for each enabled DA and not including external load on pin.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V _{VDDM}		1.85	1.95	2.1	V
Power-On Reset (POR) Threshold	V _{POR}	Rising Voltage on VDD	—	1.4	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t _{RMP}	Time to V _{DD} > 2.2 V	10	—	—	μs
Reset Delay from POR	t _{POR}	Relative to V _{DD} > V _{POR}	3	10	31	ms
Reset Delay from non-POR source	t _{RST}	Time between release of reset source and code execution	—	50	—	μs
RST Low Time to Generate Reset	t _{RSTL}		15	—	—	μs
Missing Clock Detector Response Time (final rising edge to reset)	t _{MCD}	F _{SYSClk} > 1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F _{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t _{MON}		—	2	—	μs

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	$\text{PSS}_{\text{HFOSC0}}$	$T_A = 25^\circ\text{C}$	—	0.5	—	%/V
Temperature Sensitivity	$\text{TS}_{\text{HFOSC0}}$	$V_{\text{DD}} = 3.0\text{ V}$	—	40	—	ppm/°C
High Frequency Oscillator 1 (72 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	70.5	72	73.5	MHz
Power Supply Sensitivity	$\text{PSS}_{\text{HFOSC1}}$	$T_A = 25^\circ\text{C}$	—	TBD	—	%/V
Temperature Sensitivity	$\text{TS}_{\text{HFOSC1}}$	$V_{\text{DD}} = 3.0\text{ V}$	—	TBD	—	ppm/°C
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	$\text{PSS}_{\text{LFOSC}}$	$T_A = 25^\circ\text{C}$	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	$V_{\text{DD}} = 3.0\text{ V}$	—	65	—	ppm/°C

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.10 Voltage Reference

Table 4.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}		1.62	1.65	1.68	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	μs
Power Supply Rejection	$PSRR_{\text{REFFS}}$		—	400	—	ppm/V
On-chip Precision Reference						
Valid Supply Range	V_{DD}	1.2 V Output	2.2	—	3.6	V
		2.4 V Output	2.7	—	3.6	V
Output Voltage	V_{REFP}	1.2 V Output, T = 25 °C	TBD	1.2	TBD	V
		2.4 V Output, T = 25 °C	TBD	2.4	TBD	V
Turn-on Time, settling to 0.5 LSB	t_{VREFP}	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	—	3	—	ms
		0.1 μF ceramic bypass on VREF pin	—	100	—	μs
Load Regulation	LR_{VREFP}	Load = 0 to 200 μA to GND	—	TBD	—	μV/μA
Load Capacitor	C_{VREFP}	Load = 0 to 200 μA to GND	0.1	—	—	μF
Short-circuit current	ISC_{VREFP}		—	—	8	mA
Power Supply Rejection	$PSRR_{\text{VREFP}}$		—	TBD	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	ADC Sample Rate = 1 Msps; VREF = 3.0 V	—	5	—	μA

4.1.11 Temperature Sensor

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	V_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	TBD	—	mV
Uncalibrated Offset Error ¹	E_{OFF}	$T_A = 0\text{ }^{\circ}\text{C}$	—	TBD	—	mV
Slope	M		—	2.83	—	mV/ $^{\circ}\text{C}$
Slope Error ¹	E_M		—	TBD	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity			—	TBD	—	$^{\circ}\text{C}$
Turn-on Time			—	TBD	—	μs
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset ^{2, 3}		$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	TBD	—	TBD	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-3	—	3	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	TBD	—	TBD	$^{\circ}\text{C}$

Note:

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. Temp sensor error is based upon characterization and is not tested across temperature in production. The values represent three standard deviations above and below the mean.

Table 6.1. Pin Definitions for EFM8LB1x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	VIO	I/O Supply Power Input			
3	VDD	Supply Power Input			
4	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
5	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
6	P3.4	Multifunction I/O			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
6	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5
15	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU2OUT CLU1A.15 CLU2B.14 CLU3A.14	ADC0.15 CMP1P.4 CMP1N.4
16	P2.1	Multifunction I/O	Yes	P2MAT.1 I2C0_SCL CLU1B.14 CLU2A.15 CLU3B.15	ADC0.14 CMP1P.3 CMP1N.3
17	P2.0	Multifunction I/O	Yes	P2MAT.0 I2C0_SDA CLU1A.14 CLU2A.14 CLU3B.14	CMP1P.2 CMP1N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU1OUT CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.1 CMP1N.1
20	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4 CMP1P.0 CMP1N.0
21	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9	ADC0.3 CMP0P.3 CMP0N.3
22	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8	ADC0.2 CMP0P.2 CMP0N.2
23	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
3	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
4	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
5	GND	Ground			
6	VDD / VIO	Supply Power Input			
7	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
8	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
9	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
10	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8
19	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7
20	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10	ADC0.6
21	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU1OUT CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.1 CMP1N.1
22	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4 CMP1P.0 CMP1N.0
23	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9	ADC0.3 CMP0P.3 CMP0N.3

7. QFN32 Package Specifications

7.1 QFN32 Package Dimensions

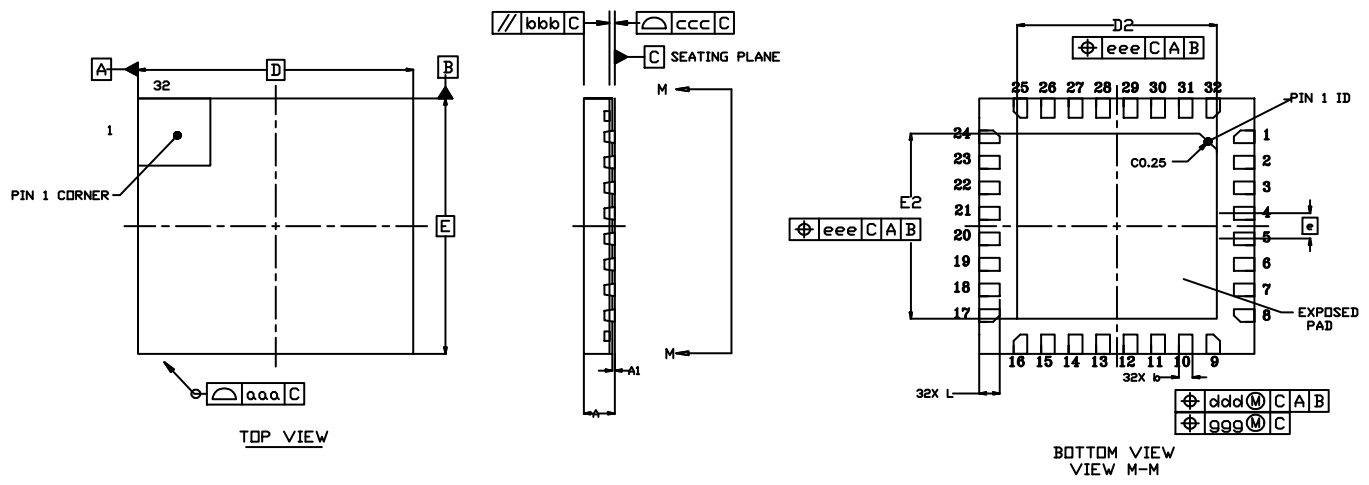


Figure 7.1. QFN32 Package Drawing

Table 7.1. QFN32 Package Dimensions

Dimension	Min	Typ	Max
A	0.45	0.50	0.55
A1	0.00	0.035	0.05
b	0.15	0.20	0.25
D	4.00 BSC.		
D2	2.80	2.90	3.00
e	0.40 BSC.		
E	4.00 BSC.		
E2	2.80	2.90	3.00
L	0.20	0.30	0.40
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10
ggg	—	—	0.05

8. QFP32 Package Specifications

8.1 QFP32 Package Dimensions

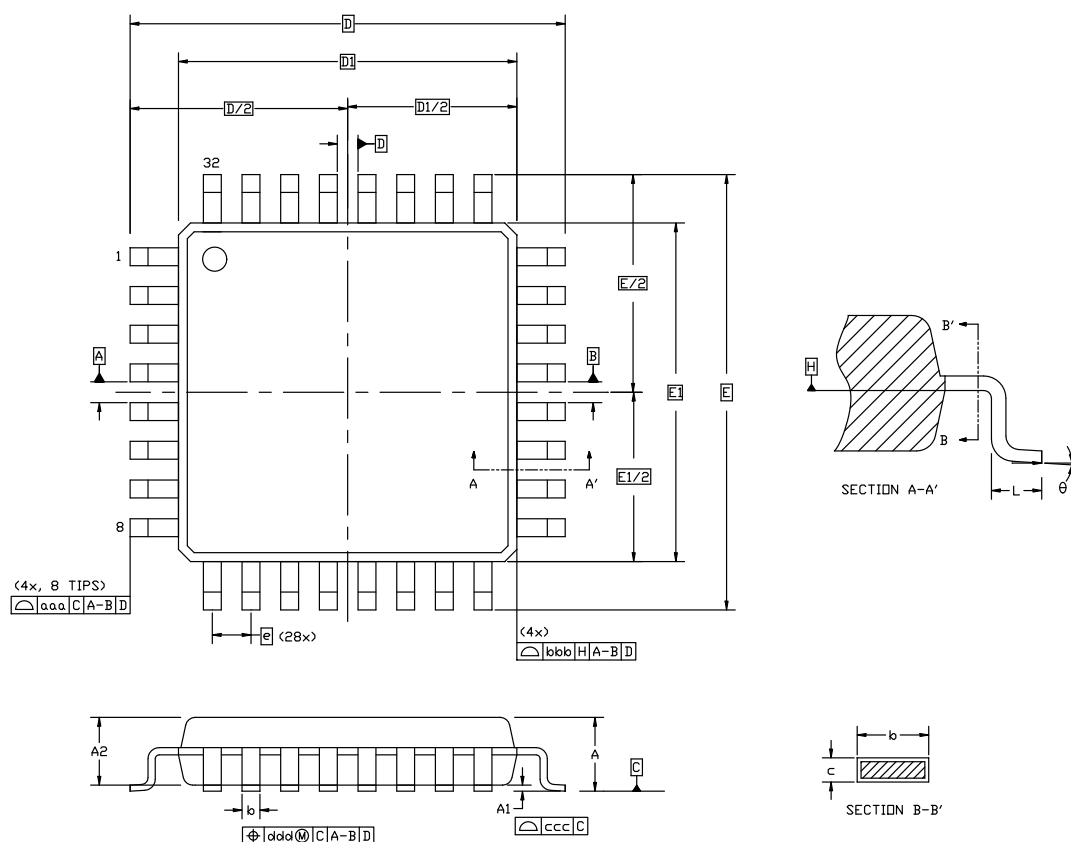


Figure 8.1. QFP32 Package Drawing

Table 8.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.30	0.37	0.45
c	0.09	—	0.20
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.50	0.60	0.70

Dimension	Min	Typ	Max
aaa	0.20		
bbb	0.20		
ccc	0.10		
ddd	0.20		
theta	0°	3.5°	7°
Note: 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994. 3. This drawing conforms to JEDEC outline MS-026. 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.			

8.3 QFP32 Package Marking

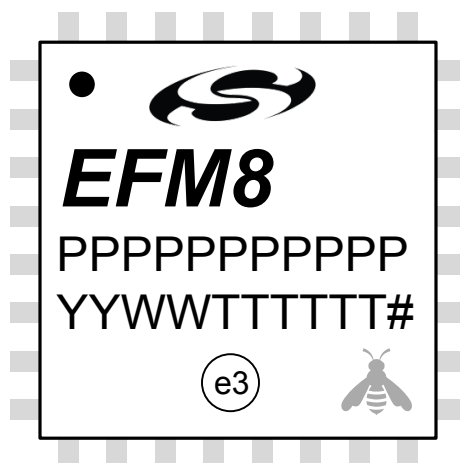


Figure 8.3. QFP32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. QFN24 Package Specifications

9.1 QFN24 Package Dimensions

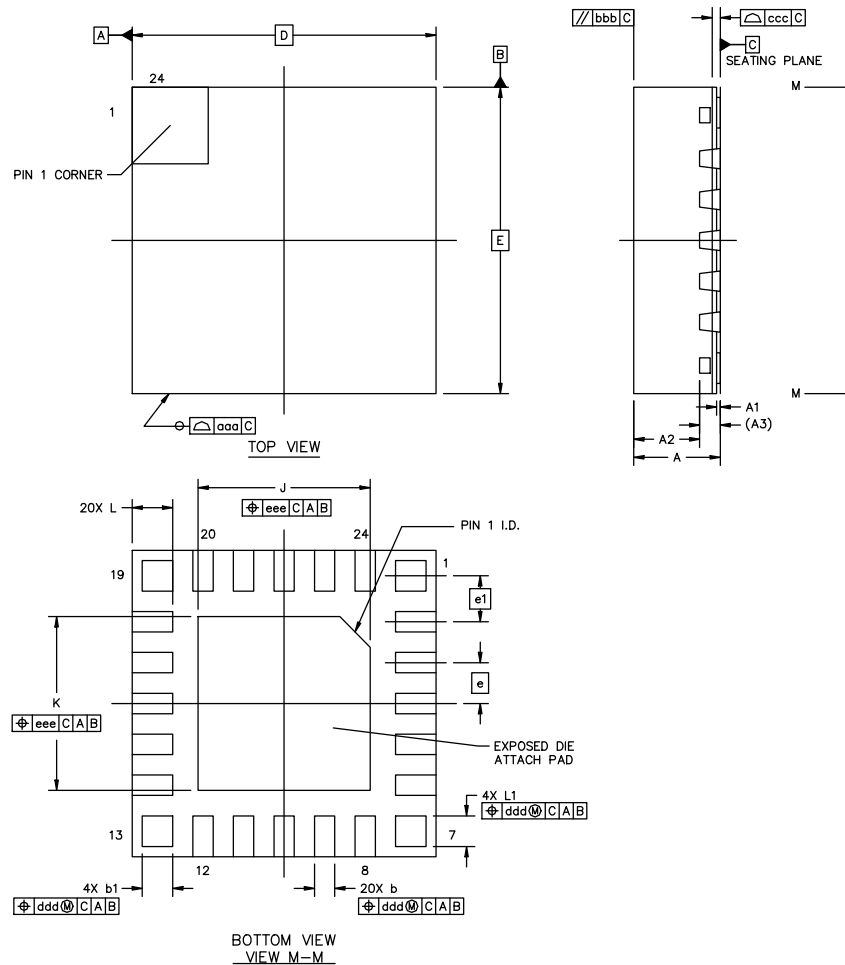


Figure 9.1. QFN24 Package Drawing

Table 9.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.8	0.85	0.9
A1	0.00	—	0.05
A2	—	0.65	—
A3	0.203 REF		
b	0.15	0.2	0.25
b1	0.25	0.3	0.35
D	3.00 BSC		
E	3.00 BSC		

Dimension	Min	Typ	Max
e	0.40 BSC		
e1	0.45 BSC		
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.2 QFN24 PCB Land Pattern

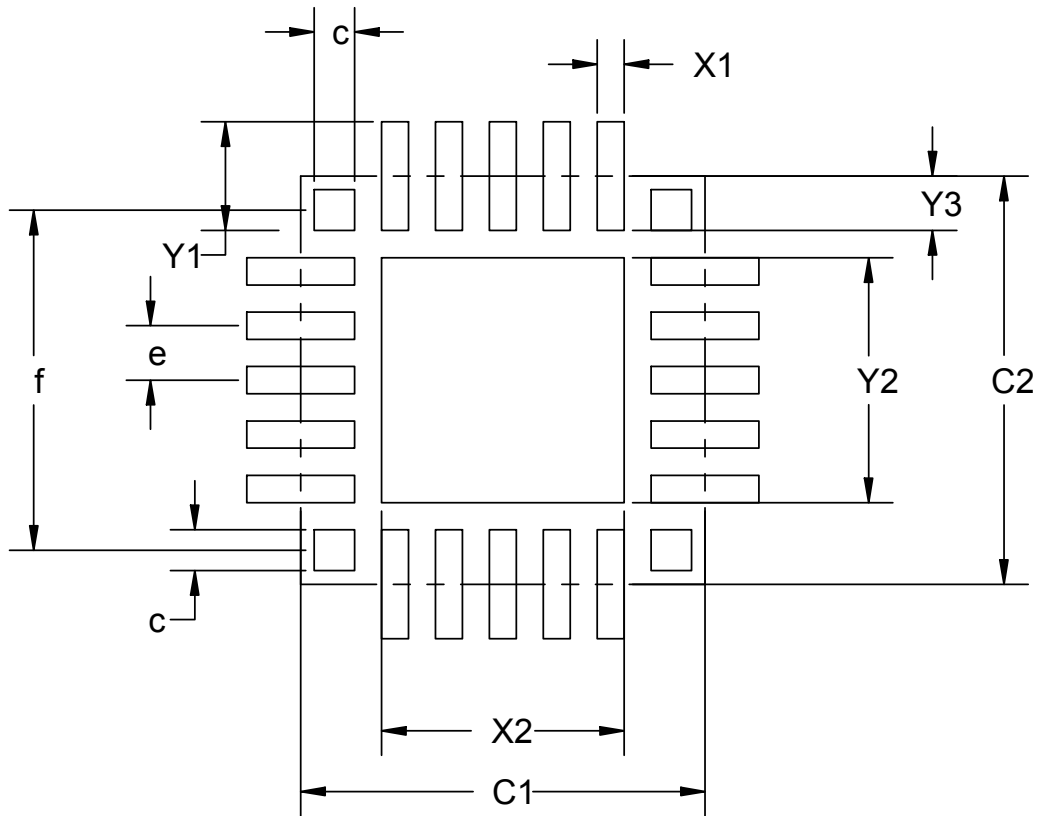


Figure 9.2. QFN24 PCB Land Pattern Drawing

Table 9.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1		3.00
C2		3.00
e		0.4 REF
X1		0.20
X2		1.80
Y1		0.80
Y2		1.80
Y3		0.4
f		2.50 REF
c	0.25	0.35

Dimension	Min	Max
Note: 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification. 3. This Land Pattern Design is based on the IPC-SM-782 guidelines. 4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad. 5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release. 6. The stencil thickness should be 0.125 mm (5 mils). 7. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads. 8. A 2 x 1 array of 1.20 mm x 0.95 mm openings on a 1.15 mm pitch should be used for the center pad. 9. A No-Clean, Type-3 solder paste is recommended. 10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.		

9.3 QFN24 Package Marking

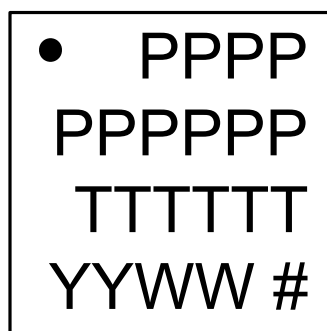


Figure 9.3. QFN24 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

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